

<b>Notice of References Cited</b>	Application/Control No. 10/568,805	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner Claire L. Rademaker	Art Unit 1795	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,101,719 A	07-1978	Uetani et al.	429/206
*	B	US-2002/0018926	02-2002	Shiga et al.	429/61
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09022732 A	01-1997	Japan	MIYASAKA et al.	H01M 10/40
	O	JP 2000299107 A	10-2000	Japan	HASEGAWA et al.	H01M 04/62
	P	JP 2003142101 A	05-2003	Japan	NUMATA et al.	H01M 04/62
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IPDL Machine Translation and Abstract in English of JP 09-022732.
	V	IPDL Machine Translation and Abstract in English of JP 2000-299107.
	W	IPDL Machine Translation and Abstract in English of JP 2003-142101.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.